## Application/Control No. Applicant(s)/Patent Under Reexamination 10/821,373 CHANG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Lenard A. Footland 3682 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2004/0131287 07-2004 Lee et al. 384/036 Α US-5,071,261 В 12-1991 Stuve, Gunther 384/36 US-С US-D US-Ε US-F US-G US-Н

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